



IMEKO

International Measurement Confederation

Technical
Committee

TC10

Technical Diagnostics

Call for papers of the Workshop on
**“New Perspectives in Measurements, Tools and
Techniques for system’s reliability, maintainability and safety”**

**MILAN, ITALY
JUNE 27-28TH 2016**

<http://www.imekotc10-2016.deib.polimi.it>

IMPORTANT DEADLINES

FEBRUARY 26, 2016

Deadline for submission of extended
abstract.

MARCH 28, 2016

Notification of authors of paper
acceptance.

MAY 2, 2016

Deadline for camera-ready papers.

INVITATION

The International Measurement Confederation IMEKO, Technical Committee 10 – Technical Diagnostics, kindly invites you to attend the 14th **IMEKO TC10 Workshop on Technical Diagnostics – “New Perspectives in Measurements, Tools and Techniques for system’s reliability, maintainability and safety”** to be held in **Milan, Italy, on June 27-28, 2016**. The Workshop is a forum for advancing knowledge and exchange ideas on methods, principles, instruments and tools, standards and industrial applications on Technical Diagnostics as well as their diffusion across the scientific community. Participants have an excellent opportunity to meet top specialists from industry and academia all over the world and to enhance their international co-operation. The program will feature industry leading keynote speakers and selected presentations.

CALL FOR PAPERS

Authors are kindly invited to submit extended abstracts on the topics listed below, three to four pages long in A4 format. The abstract should report original research results of theoretical or applied nature and should explain the significance of the contribution to the research field. The abstracts will be reviewed by the International Program Committee. Electronic abstracts must be in Adobe Acrobat (pdf) and should be sent according to the procedure described in <http://www.imekotc10-2016.deib.polimi.it>

SPECIAL ISSUE

The presented papers at IMEKO TC10 are eligible for submission to the Measurement and ACTA IMEKO Special Issues. All submitted papers will undergo a regular peer review process. The manuscript **MUST** be significantly technically extended beyond the proceedings paper.

TOPICS

- basic principles and development trends in technical diagnostics
- condition monitoring and maintenance of industrial process, plants and complex systems
- innovative sensors, data acquisition systems and signal processing
- technical diagnostics and prognostics
- safety critical systems
- diagnostics for Maintainability, Safety, Risk assessment and management
- non destructive testing
- artificial intelligence techniques and machine learning for diagnostics
- diagnostics applications in transportation, mechatronics, avionics, automotive, biomedics and IT
- decision support and IT solutions for diagnosis
- diagnostics for the improvement of quality of life and environment
- industrial standards
- industrial applications of monitoring and supervision systems



GENERAL CHAIRS

Prof.
Loredana Cristaldi
DEIB Department
Politecnico di Milano
loredana.cristaldi@polimi.it

Prof.
Marcantonio Catelani
Information Engineering
Department
University of Florence
marcantonio.catelani@unifi.it

TECHNICAL PROGRAM CHAIR

Dr.
Lorenzo Ciani
Information Engineering Department
University of Florence
lorenzo.ciani@unifi.it